IEEE HVCB PC37.06.1 2011-10-10

Chair: Keith Wallace Meeting Location Nashville, TN
Vice Chair Bill Bergman

1. Introductions of all attendees
2. Attendance list circulated
3. The IEEE Patent slides and Guidelines for IEEE WG meetings were reviewed
4. Scope of existing document states "This recommended practice supplements IEEE C37.06 for high-voltage circuit breaker applications where the transient recovery voltages rise to the crest value more rapidly than those specified in C37.06." The document will be a "Recommended Practice" rather than a "Guide".
5. The intention is to apply this recommended practice using 10% and 30% (to align with C37.06) rather than the existing C37.06.1 values of 7% and 30%. Discussion followed on whether testing at 10% can be extrapolated back to 7% and lower values. Can a test at a more severe condition be used to demonstrate a less severe condition? Generally, the inductance must increase on a system to yield reduced fault current; however, there is a limit on how much the corresponding capacitance can be reduced. The di/dt generally increases as the fault current is reduced ($1/\sqrt{LC}$) for terminal faults and decreases for reduced line fault currents. TRVs for currents more than 30% of rated short-circuit current remain the same as for C37.06.
6. Discussion recommended deleting Col 2, Col 4 and Col 5 from Table. Add time delay of 15% of t_3. Add t_d to figure.
7. WG discussion resulted in general agreement to develop an Annex with the historical source of values in the original tables of C37.06.1.
8. Keith Wallace will have a draft PC37.06.1 issued by the end of 2011 for WG review.